

#### SLOVENSKI STANDARD SIST ISO 7503-2:2025

01-januar-2025

Merjenje radioaktivnosti - Merjenje in vrednotenje površinske kontaminacije - 2. del: Preskusna metoda z uporabo vzorcev za brisanje

Measurement of radioactivity - Measurement and evaluation of surface contamination - Part 2: Test method using wipe-test samples

iTeh Standards

Mesurage de la radioactivité — Mesurage et évaluation de la contamination de surface — Partie 2: Méthode d'essai utilisant des échantillons d'essai de frottis

Ta slovenski standard je istoveten z: ISO 7503-2:2016

ICS:

13.280 Varstvo pred sevanjem Radiation protection

SIST ISO 7503-2:2025 en.fr

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# INTERNATIONAL STANDARD

ISO 7503-2

Second edition 2016-01-15

# Measurement of radioactivity - Measurement and evaluation of surface contamination —

Part 2: **Test method using wipe-test samples** 

Mesurage de la radioactivité — Mesurage et évaluation de la contamination de surface —

Partie 2: Méthode d'essai utilisant des échantillons d'essai de frottis

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#### ISO 7503-2:2016(E)

#### **Foreword**

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The committee responsible for this document is Technical Committee ISO/TC 85, *Nuclear energy, nuclear technologies, and radiological protection*, Subcommittee SC 2, *Radiological protection*.

This second edition cancels and replaces the first edition (ISO 7503-2:1988), which has been technically revised.

ISO 7503 consists of the following parts, under the general title *Measurement of radioactivity* — *Measurement and evaluation of surface contamination*:

- Part 1: General principles
- Part 2: Test method using wipe-test samples
- Part 3: Apparatus calibration